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- Inputs Are TTL-Voltage Compatible
- Lock Bus-Latch Capability
- True Logic
- High-Current 3-State Outputs Can Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W)
 Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
 300-mil DIPs

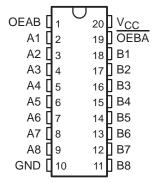
description

These octal bus transceivers are designed for asynchronous two-way communication between data buses. The control-function implementation allows for maximum flexibility in timing.

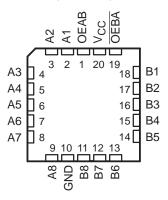
The 'HCT623 allow data transmission from the A bus to the B bus or from the B bus to the A bus, depending upon the logic levels at the output-enable (OEAB and OEBA) inputs.

The output-enable inputs disable the device so that the buses are effectively isolated. The dual-enable configuration gives the transceivers the capability to store data by simultaneously enabling OEAB and OEBA. Each output reinforces its input in this transceiver configuration. When both OEAB and OEBA are enabled and all other data sources to the two sets of bus lines are in the high-impedance state, both sets of bus lines (16 total) remain at their last states. The 8-bit codes appearing on the two sets of buses are identical.

SN54HCT623 ... J OR W PACKAGE SN74HCT623 ... DW OR N PACKAGE (TOP VIEW)



SN54HCT623 . . . FK PACKAGE (TOP VIEW)



The SN54HCT623 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74HCT623 is characterized for operation from -40° C to 85° C.

FUNCTION TABLE

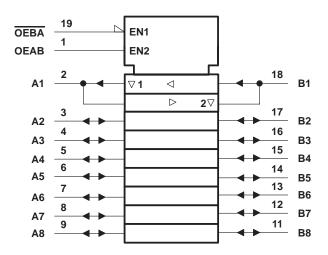
INP	UTS	OPERATION			
OEBA	OEAB	OPERATION			
L	L	B data to A bus			
Н	Н	A data to B bus			
Н	L	Isolation			
L	Н	B data to A bus, A data to B bus			



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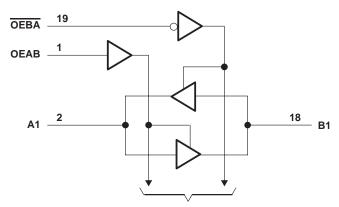


logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Transceivers

absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}	0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{sto}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			SN	54HCT6	23	SN	74HCT6	23	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	V _{CC} = 4.5 V to 5.5 V	2	N.		2			V
V _{IL}	Low-level input voltage	V _{CC} = 4.5 V to 5.5 V	0	Q ²	0.8	0		0.8	V
٧ _I	Input voltage		0	70	VCC	0		VCC	V
٧o	Output voltage		0 4	2	VCC	0		VCC	V
t _t	Input transition (rise and fall) time		0)	500	0		500	ns
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DAD	METER	TEST CONDITIONS		Vaa	T _A = 25°C			SN54HCT623		SN74HCT623		
PARAMETER		TEST CONDITIONS		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
VOH		\\ \\ or \\.	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
VOH		$V_I = V_{IH}$ or V_{IL}	I _{OH} = -6 mA	4.5 V	3.98	4.3		3.7		3.84		V
\/a.		\/ \/ or \/	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
VOL		$V_I = V_{IH}$ or V_{IL}	$I_{OL} = 6 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	V
Ц	OEAB or OEBA	VI = VCC or 0		5.5 V		±0.1	±100	4	±1000		±1000	nA
loz	A or B	$V_O = V_{CC}$ or GND		5.5 V		±0.01	±0.5	02	±10		±5	μΑ
Icc		$V_I = V_{CC}$ or 0,	IO = 0	5.5 V			8	20	160		80	μΑ
ΔICC [†]		One input at 0.5 V or 2 Other inputs at 0 or V		5.5 V		1.4	2.4	Yd	3		2.9	mA
Ci	OEAB or OEBA			4.5 V to 5.5 V		3	10		10		10	pF

[†] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	V	T	λ = 25°C	;	SN54H0	CT623	SN74H	CT623	UNIT				
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT				
.	A or B	B or A	4.5 V		15	22		33		28	ns				
^t pd	AOIB	BOIA	5.5 V		13	20		30		25	115				
+		А	4.5 V		30	42		63		53	ns				
^t en	OEBA	A	5.5 V		23	38		57		48	110				
+	ŌEBĀ	А	4.5 V		18	30	,	45		38	ns				
^t dis		OEBA	OEBA	OEBA	OEBA	OEBA	A	5.5 V		16	28	4	42		35
	OEAB	В	4.5 V		30	42	37	63		53	ns				
t _{en}	OEAB	OEAB	Ь	5.5 V		23	38	70 ₆	57		48	115			
*	OEAB	В	4.5 V		18	30	ď	45		38	nc				
^t dis	OEAB	Ь	5.5 V		16	28		42		35	ns				
+.		A or B	4.5 V		9	12		18		15					
t _t		A OL B	5.5 V		8	11		16		14	ns				

SN54HCT623, SN74HCT623 OCTAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

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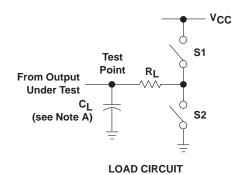
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER FROM (INPUT)		то	FROM TO $T_A = 25^{\circ}C$;	SN54HCT623	SN74HCT623	UNIT	
		(OUTPUT)	VCC	MIN	TYP	MAX	MIN MAX	MIN MAX	UNIT
	A or B	P.or A	4.5 V		18	38	58	47	
^t pd	AUID	B or A	5.5 V		11	34	52	42	ns
	. OEBA	А	4.5 V		36	59	89	74	
			5.5 V		30	53	80	67	no
^t en	OEAB	В	4.5 V		36	59	\$ 89	74	ns
	UEAB	Ь	5.5 V		30	53	80	67	
t _t		A D	4.5 V		17	42	63	53	no
	A or B	AUID	5.5 V		14	38	57	48	ns

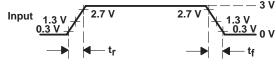
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per transceiver	No load	40	pF

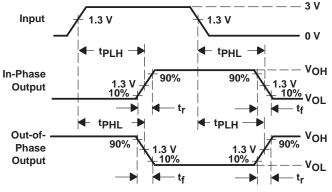
PARAMETER MEASUREMENT INFORMATION

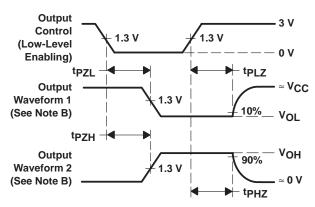


PARAMETER		RL	CL	S 1	S2	
	tPZH	50 pF 1 kΩ or		Open	Closed	
^t en	tPZL	1 K22	150 pF	Closed	Open	
* II.	tPHZ	1 kΩ	50 pF	Open	Closed	
^t dis	tPLZ	1 K22	30 pr	Closed	Open	
t _{pd} or t _t		l	50 pF or 150 pF	Open	Open	



VOLTAGE WAVEFORM INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z $_{O}$ = 50 $\Omega,$ t_{f} = 6 ns, t_{f} = 6 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tp7I and tp7H are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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